

- **3:21 Data Channel Expansion at up to 163 Million Bytes per Second Throughput**
- **Suited for SVGA, XGA, or SXGA Display Data Transmission From Controller to Display With Very Low EMI**
- **3 Data Channels and Clock Low-Voltage Differential Channels In and 21 Data and Clock Low-Voltage TTL Channels Out**
- **Operates From a Single 3.3-V Supply**
- **Tolerates 4-kV HBM ESD**
- **Packaged in Thin Shrink Small-Outline Package (TSSOP) With 20-Mil Terminal Pitch**
- **Consumes Less Than 1 mW When Disabled**
- **Wide Phase-Lock Input Frequency Range 31 MHz to 68 MHz**
- **No External Components Required for PLL**
- **Inputs Meet or Exceed the Standard Requirements of ANSI EIA/TIA-644 Standard**
- **Improved Replacement for the DS90C364 and SN75LVDS86**
- **Improved Jitter Tolerance**

description

The SN75LVDS86A FlatLink receiver contains three serial-in 7-bit parallel-out shift registers and four low-voltage differential signaling (LVDS) line receivers in a single integrated circuit. These functions allow receipt of synchronous data from a compatible transmitter, such as the SN75LVDS81, '83, '84, or '85, over four balanced-pair conductors and expansion to 21 bits of single-ended low-voltage LVTTTL synchronous data at a lower transfer rate.

When receiving, the high-speed LVDS data is received and loaded into registers at seven times the LVDS input clock (CLKIN) rate. The data is then unloaded to a 21-bit wide LVTTTL parallel bus at the CLKIN rate. The SN75LVDS86A presents valid data on the falling edge of the output clock (CLKOUT).

The SN75LVDS86A requires only four line-termination resistors for the differential inputs and little or no control. The data bus appears the same at the input to the transmitter and output of the receiver with the data transmission transparent to the user(s). The only user intervention is the possible use of the shutdown/clear (SHTDN) active-low input to inhibit the clock and shut off the LVDS receivers for lower power consumption. A low level on this signal clears all internal registers to a low level.

The SN75LVDS86A is characterized for operation over ambient free-air temperatures of 0°C to 70°C.

DGG PACKAGE (TOP VIEW)

D17	1	48	V _{CC}
D18	2	47	D16
GND	3	46	D15
D19	4	45	D14
D20	5	44	GND
NC	6	43	D13
LVDSGND	7	42	V _{CC}
A0M	8	41	D12
A0P	9	40	D11
A1M	10	39	D10
A1P	11	38	GND
LVDSV _{CC}	12	37	D9
LVDSGND	13	36	V _{CC}
A2M	14	35	D8
A2P	15	34	D7
CLKINM	16	33	D6
CLKINP	17	32	GND
LVDSGND	18	31	D5
PLL _{GND}	19	30	D4
PLL _{V_{CC}}	20	29	D3
PLL _{GND}	21	28	V _{CC}
SHTDN	22	27	D2
CLKOUT	23	26	D1
D0	24	25	GND

NC – Not connected

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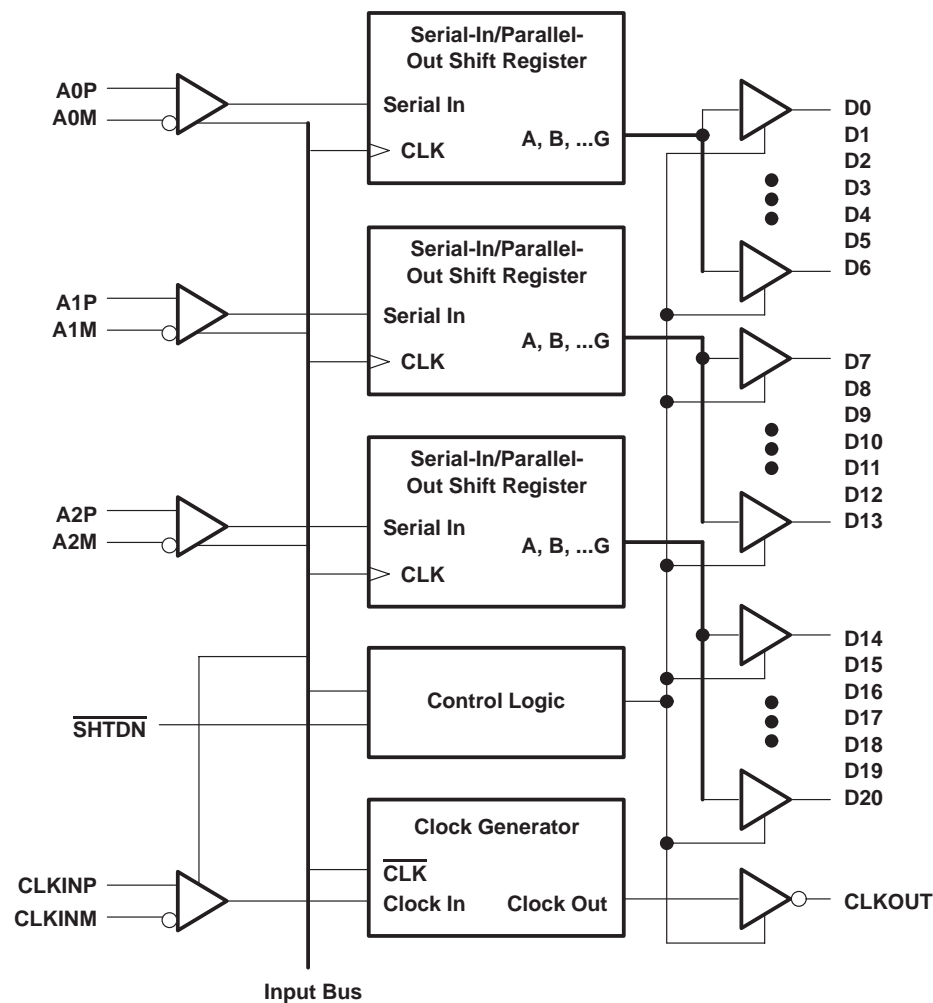
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functional block diagram



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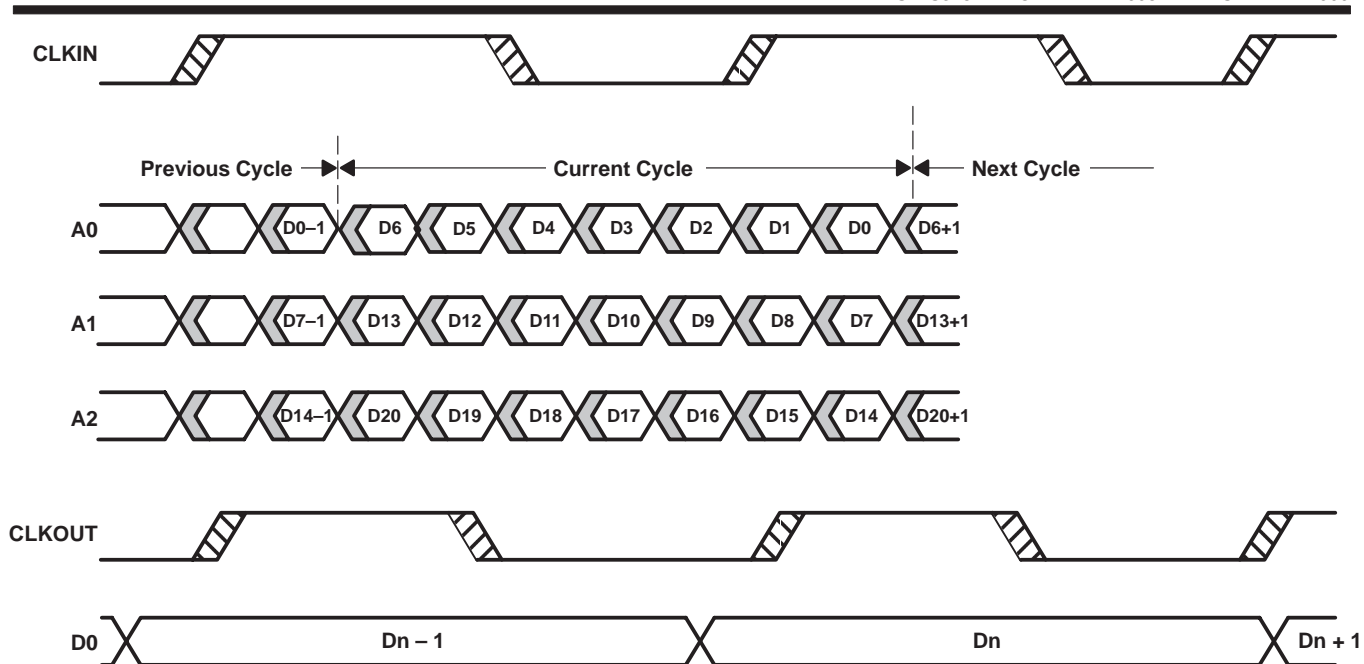
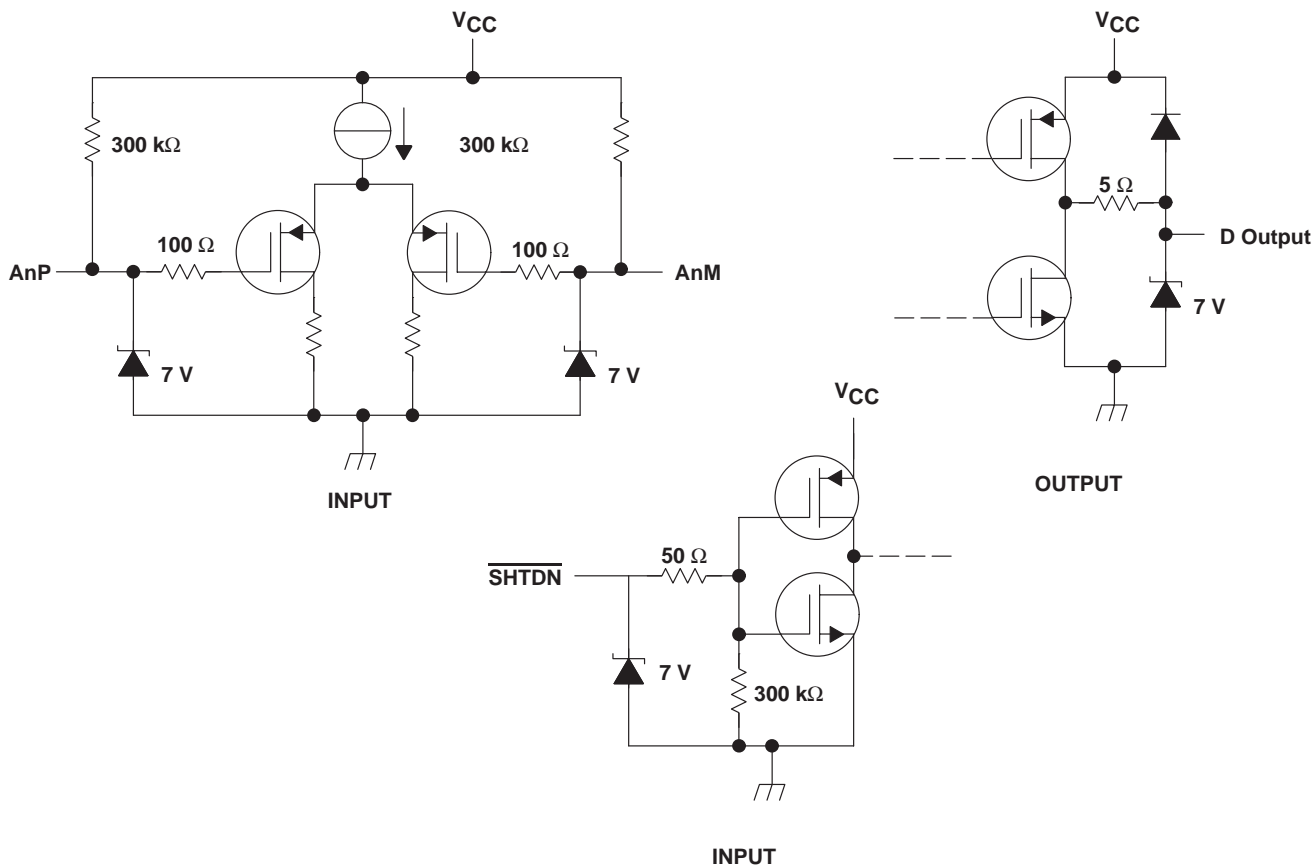


Figure 1. SN75LVDS86A Load and Shift Timing Sequences

equivalent input and output schematic diagrams



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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V_{CC} (see Note 1)	–0.5 V to 4 V
Voltage range at any terminal	–0.5 V to $V_{CC} + 0.5$ V
Electrostatic discharge (see Note 2): All pins (Class 3A)	4 kV
All pins (Class 2B)	200 V
Continuous total power dissipation	See Dissipation Rating Table
Storage temperature range, T_{stg}	–65°C to 150°C
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds	260°C

† Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. All voltage values are with respect to the GND terminals unless otherwise noted.
2. This rating is measured using MIL-STD-883C Method, 3015.7.

DISSIPATION RATING TABLE

PACKAGE	$T_A \leq 25^\circ\text{C}$ POWER RATING	DERATING FACTOR‡ ABOVE $T_A = 25^\circ\text{C}$	$T_A = 70^\circ\text{C}$ POWER RATING
DGG	1316 mW	13.1 mW/°C	726 mW

‡ This is the inverse of the junction-to-ambient thermal resistance when board mounted and with no air flow.

recommended operating conditions (see Figure 2)

	MIN	NOM	MAX	UNIT
Supply voltage, V_{CC}	3	3.3	3.6	V
High-level input voltage, V_{IH} (SHTDN)	2			V
Low-level input voltage, V_{IL} (SHTDN)			0.8	V
Magnitude differential input voltage, $ V_{ID} $	0.1		0.6	V
Common-mode input voltage, V_{IC}	$\frac{ V_{ID} }{2}$	$2.4 - \frac{ V_{ID} }{2}$		V
Operating free-air temperature, T_A	0		70	°C

timing requirements

	MIN	NOM	MAX	UNIT
Cycle time, input clock, t_C §	14.7	t_C	32.4	ns

§ Parameter t_C is defined as the mean duration of a minimum of 32 000 clock cycles.

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electrical characteristics over recommended operating conditions (unless otherwise noted)

PARAMETER	TEST CONDITIONS	MIN	TYP†	MAX	UNIT
V_{IT+} Positive-going differential input threshold voltage				100	mV
V_{IT-} Negative-going differential input threshold voltage‡		-100			mV
V_{OH} High-level output voltage	$I_{OH} = -4$ mA	2.4			V
V_{OL} Low-level output voltage	$I_{OL} = 4$ mA			0.4	V
I_{CC} Quiescent current (average)	Disabled, All inputs to GND			280	μA
	Enabled, AnP = 1 V, AnM = 1.4 V, $t_C = 15.38$ ns		33	40	mA
	Enabled, $C_L = 8$ pF, Grayscale pattern (see Figure 3), $t_C = 15.38$ ns		43		mA
	Enabled, $C_L = 8$ pF, Worst-case pattern (see Figure 4) $t_C = 15.38$ ns		68		mA
I_{IH} High-level input current (\overline{SHTDN})	$V_{IH} = V_{CC}$			±20	μA
I_{IL} Low-level input current (\overline{SHTDN})	$V_{IL} = 0$			±20	μA
I_I Input current A inputs	$0 \leq V_I \leq 2.4$ V			±20	μA
I_{OZ} High-impedance output current	$V_O = 0$ or V_{CC}			±10	μA

† All typical values are at $V_{CC} = 3.3$ V, $T_A = 25^\circ\text{C}$.

‡ The algebraic convention, in which the less-positive (more-negative) limit is designated minimum, is used in this data sheet for the negative-going input voltage threshold only.

switching characteristics over recommended operating conditions (unless otherwise noted)

PARAMETER	TEST CONDITIONS	MIN	TYP†	MAX	UNIT
t_{su} Setup time, D0 – D20 to CLKOUT↓	$C_L = 8$ pF, See Figure 5	5			ns
t_h Data hold time, CLKOUT↓ to D0 – D20		5			ns
$t_{(RSKM)}$ Receiver input skew margin§ (see Figure 7)	$t_C = 15.38$ ns ($\pm 0.2\%$), Input clock jitter < 50 ps¶	550	700		ps
t_d Delay time, CLKIN↑ to CLKOUT↓ (see Figure 7)	$V_{CC} = 3.3$ V, $t_C = 15.38$ ns ($\pm 0.2\%$), $T_A = 25^\circ\text{C}$	3	5	7	ns
t_{en} Enable time, \overline{SHTDN} to phase lock	See Figure 7		1		ms
t_{dis} Disable time, \overline{SHTDN} to off state	See Figure 8		400		ns
t_t Transition time, output (10% to 90% t_r or t_f) (data only)	$C_L = 8$ pF		3		ns
t_t Transition time, output (10% to 90% t_r or t_f) (clock only)	$C_L = 8$ pF		1.5		ns
t_w Pulse duration, output clock			0.50 t_C		ns

† All typical values are at $V_{CC} = 3.3$ V, $T_A = 25^\circ\text{C}$.

§ The parameter $t_{(RSKM)}$ is the timing margin available to allocate to the transmitter and interconnection skews and clock jitter. The value of this parameter at clock periods other than 15.38 ns can be calculated from $t_{(RSKM)} = t_C/14 - 550$ ps.

¶ |Input clock jitter| is the magnitude of the change in input clock period.

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PARAMETER MEASUREMENT INFORMATION

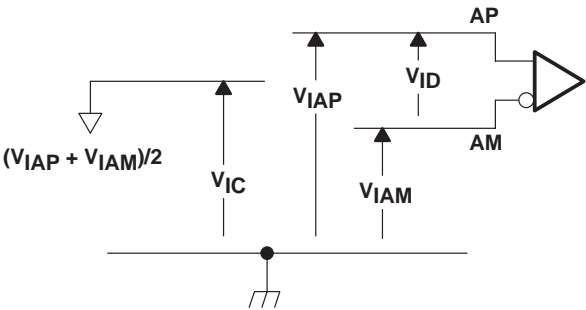
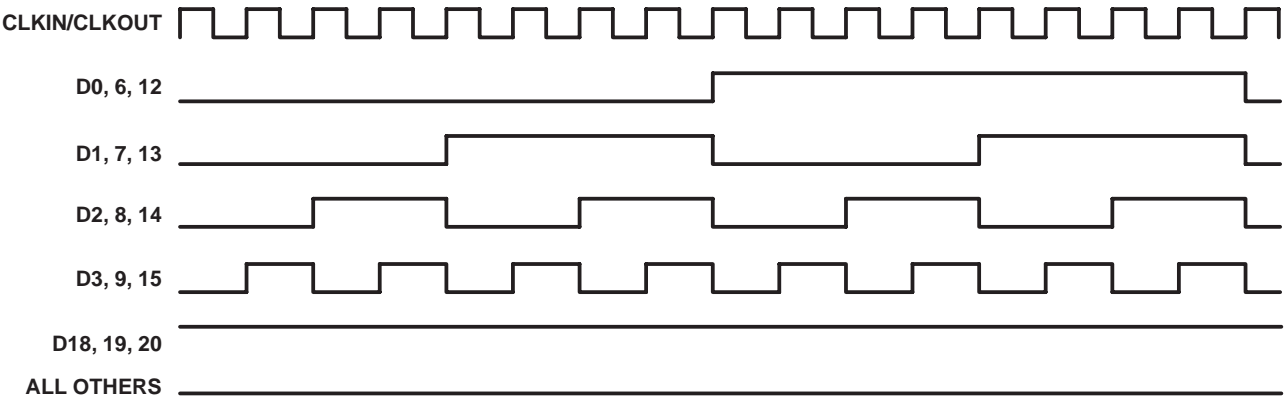
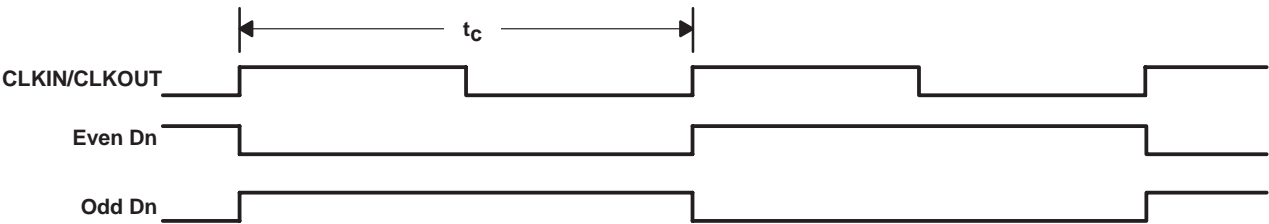


Figure 2. Voltage Definitions



NOTE A: The 16-grayscale test-pattern test device power consumption for a typical display pattern.

Figure 3. 16-Grayscale Test-Pattern Waveforms



NOTE A: The worst-case test pattern produces nearly the maximum switching frequency for all of the LVTTTL outputs.

Figure 4. Worst-Case Test-Pattern Waveforms

PARAMETER MEASUREMENT INFORMATION

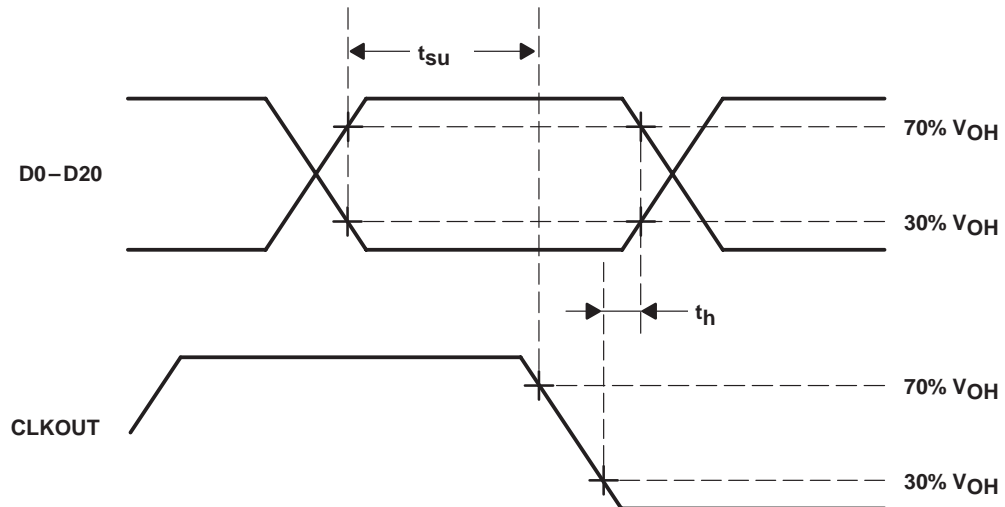
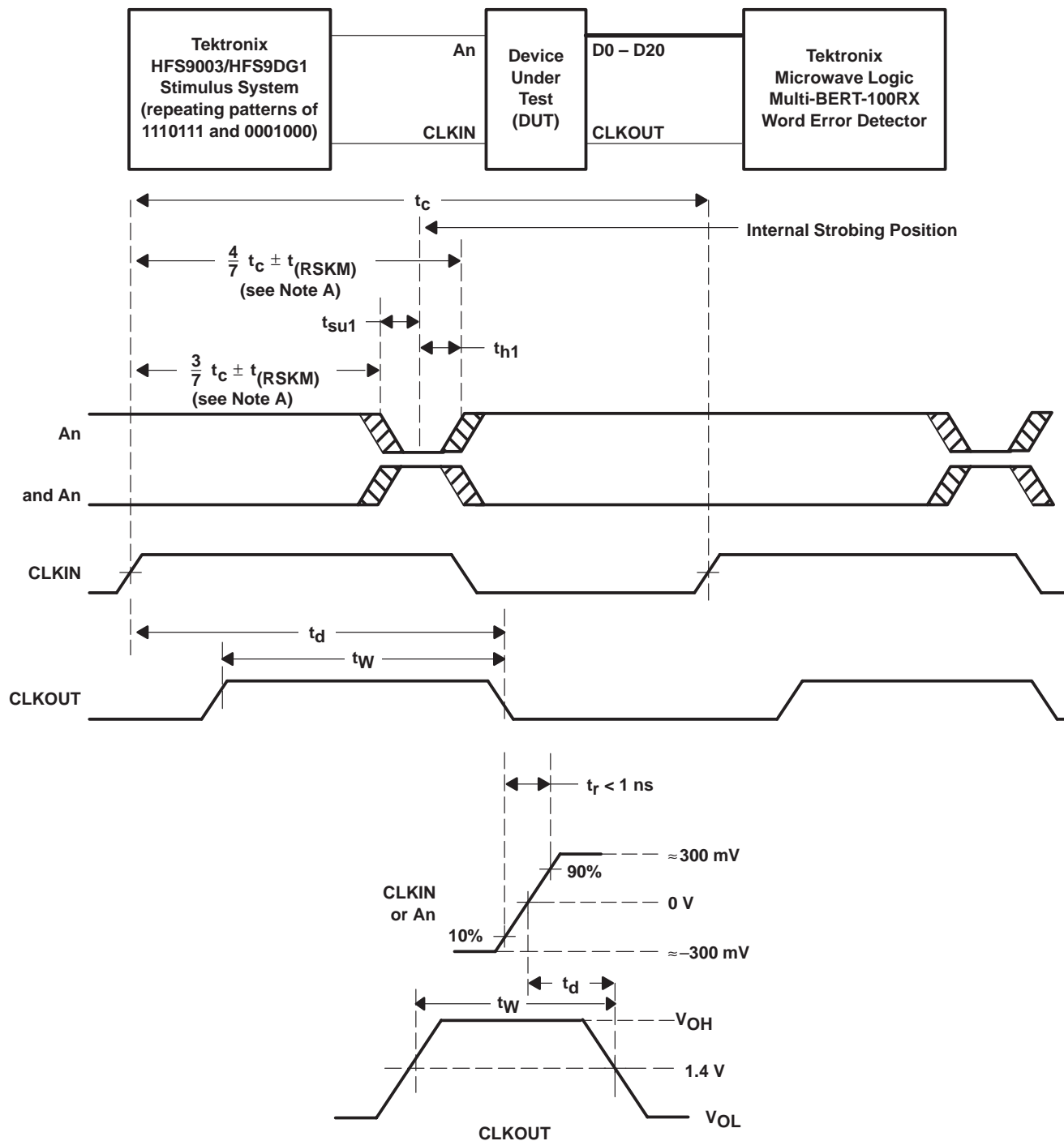


Figure 5. Setup and Hold Time Waveforms

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PARAMETER MEASUREMENT INFORMATION



NOTE A: CLKIN is advanced or delayed with respect to data until errors are observed at the receiver outputs. The advance or delay is then reduced until there are no data errors observed. The magnitude of the advance or delay is $t_{(RSKM)}$.

Figure 6. Receiver Input Skew Margin, Setup/Hold Time, and Delay Time Definitions

PARAMETER MEASUREMENT INFORMATION

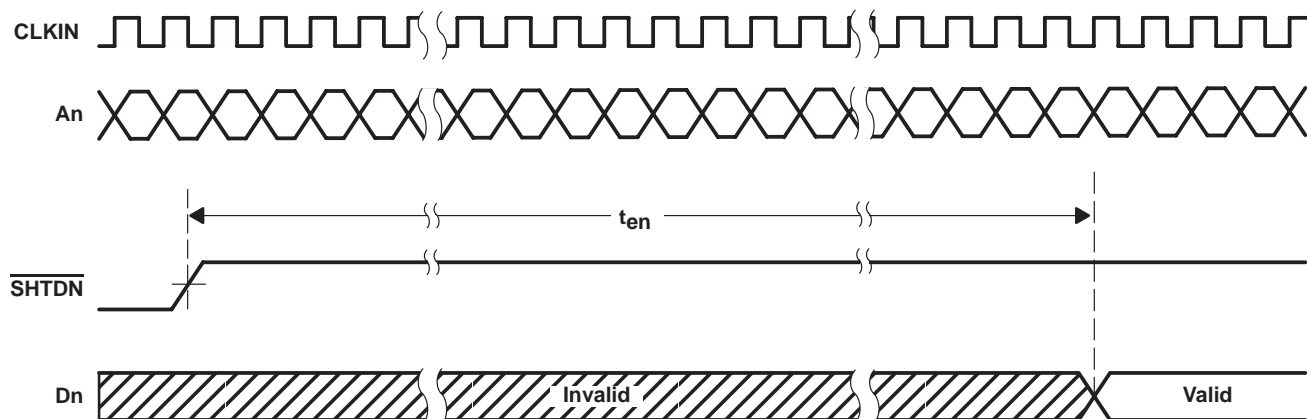


Figure 7. Enable Time Waveforms

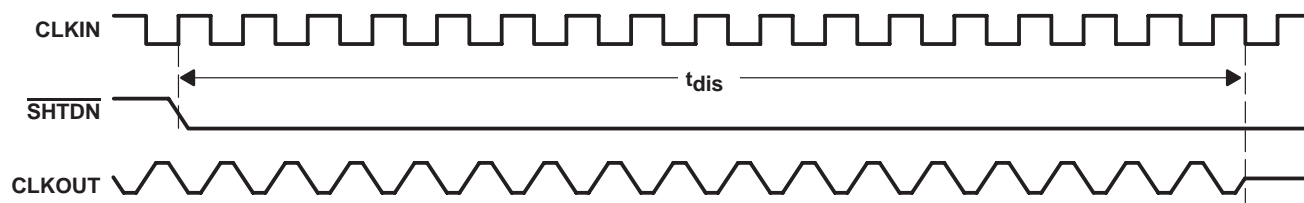


Figure 8. Disable Time Waveforms

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TYPICAL CHARACTERISTICS

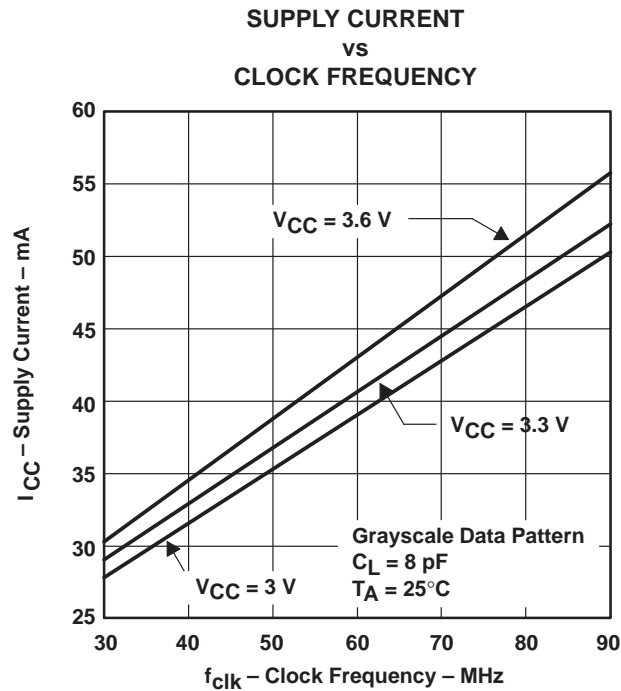
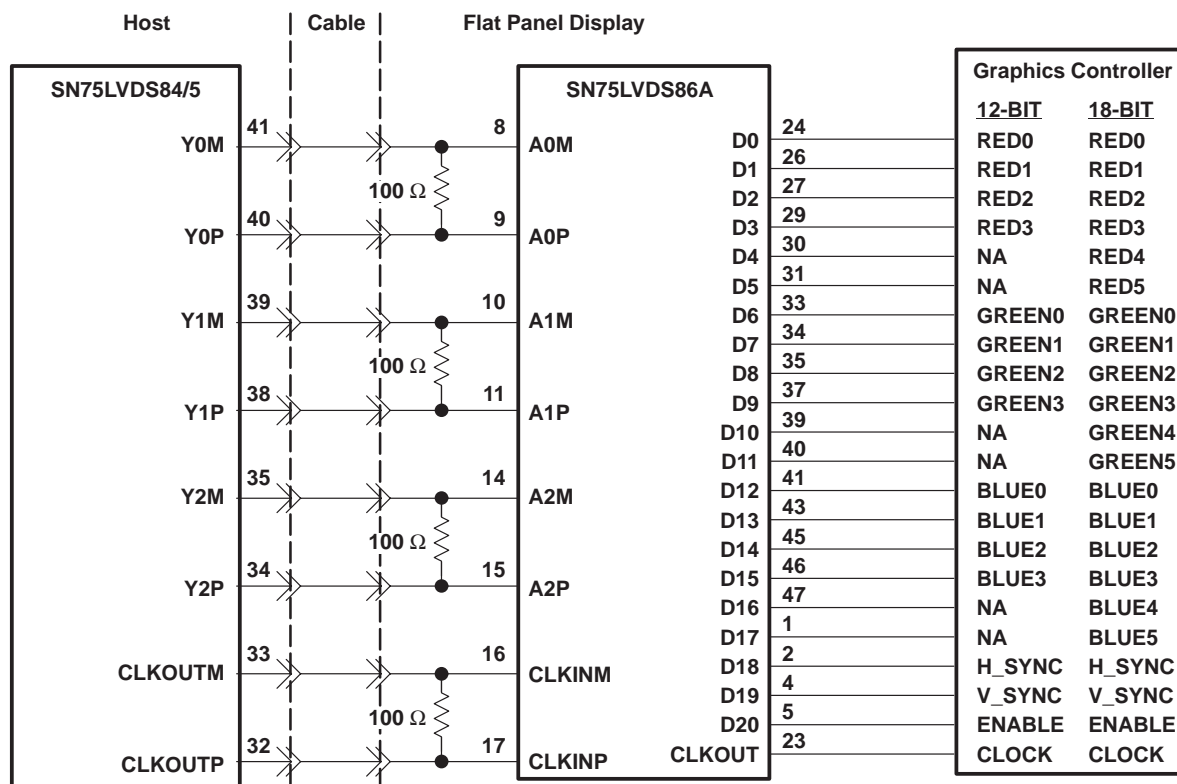


Figure 9. RMS Grayscale I_{CC} vs Clock Frequency

APPLICATION INFORMATION



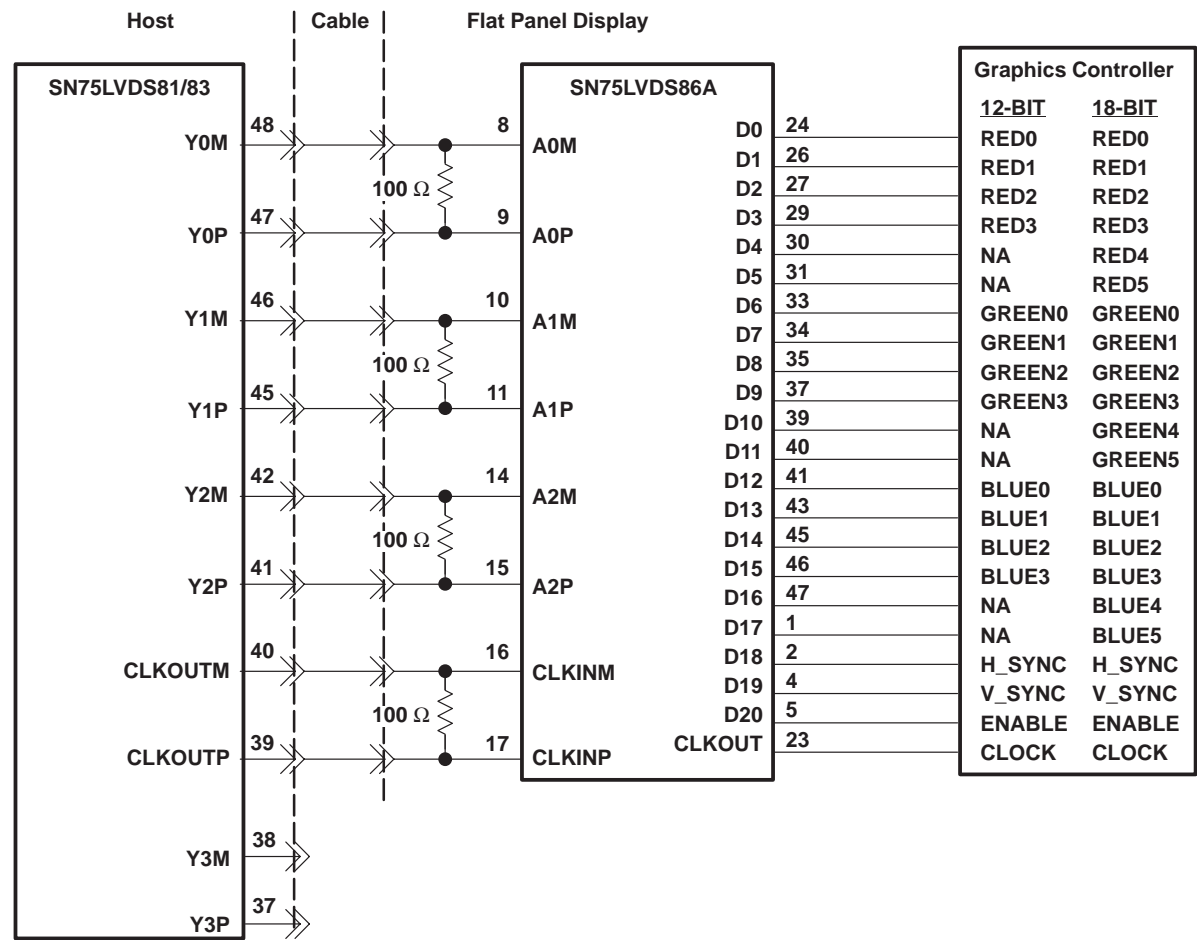
- NOTES: A. The four 100-Ω terminating resistors are recommended to be 0603 types.
B. NA – not applicable, these unused inputs should be left open.

Figure 10. 18-Bit Color Host to Flat Panel Display Application

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APPLICATION INFORMATION



NOTES: A. The four 100-Ω terminating resistors are recommended to be 0603 types.
B. NA – not applicable, these unused inputs should be left open.

Figure 11. 24-Bit Color Host to 18-Bit Color LCD Panel Display Application

See the *FLaTLink Designer's Guide* (SLLA012) for more application information.

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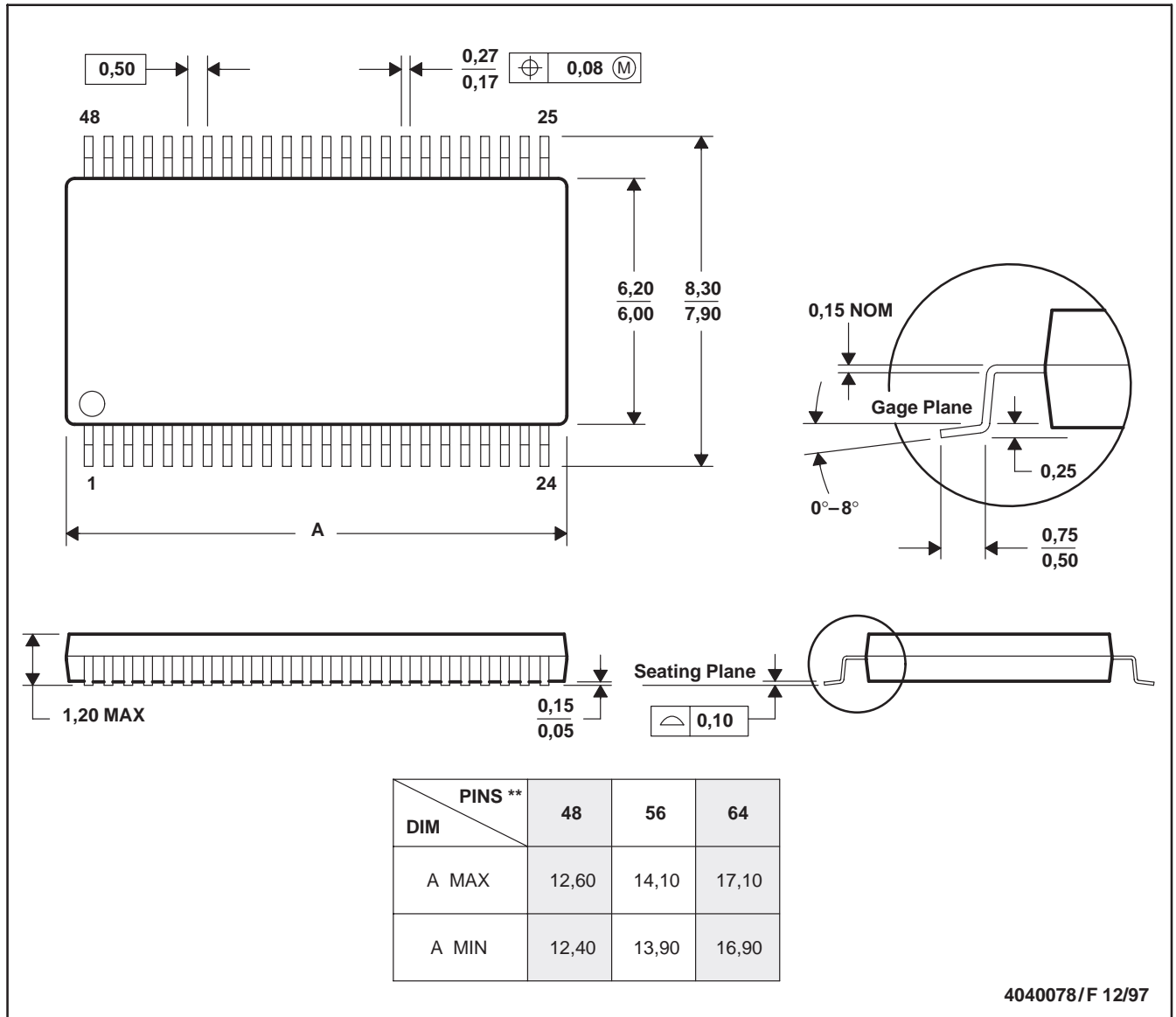
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MECHANICAL INFORMATION

DGG (R-PDSO-G**)

PLASTIC SMALL-OUTLINE PACKAGE

48 PIN SHOWN



- NOTES:
- A. All linear dimensions are in millimeters.
 - B. This drawing is subject to change without notice.
 - C. Body dimensions do not include mold protrusion not to exceed 0,15.
 - D. Falls within JEDEC MO-153

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